

Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 119243	APPLICATION NO. 10/808,523	
<p style="text-align: center;">O 1 P INFORMATION DISCLOSURE STATEMENT</p> <p>Use several sheets if necessary)</p> <p>OCT 05 2005</p> <p>PATENT & TRADEMARK OFFICE</p>				APPLICANT Hiroyuki HARA		
				FILING DATE March 25, 2004	GROUP 2858	
U.S. PATENT DOCUMENTS						
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
<i>MK</i>	1	4,429,413	01/31/1984	David G. EDWARDS		
<i>MK</i>	2	6,049,620	04/11/2000	Alexander G. DICKINSON		
FOREIGN PATENT DOCUMENTS						
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS
<i>MK</i>	3	EP 1 041 356 A1	10/04/2000	Europe		
	4	EP 0 969 477 A1	01/05/2000	Europe		
	5	JP A 58-27277 (w/Partial Eng. Trans. & Corresponding to U.S. 4,429,413)	02/17/1983	Japan		
	6	JP A 2000-028311 (w/Eng. Abstract and Translation)	01/28/2000	Japan		
	7	JP A 2002-340517 (w/Eng. Abstract and Translation)	11/27/2002	Japan		
	8	JP A 2003-090703 (w/Eng. Abstract and Translation)	03/28/2003	Japan		
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)						
<i>MK</i>	9	Hiroyuki HARA et al., "Low Temperature Polycrystalline Silicon TFT Fingerprint Sensor with Integrated Comparator Circuit", IEEE, September 21-23, 2004, pages 403-406.				
<i>MK</i>	10	Ryuichi HASHIDO et al., "A Capacitive Fingerprint Sensor Chip Using Low-Temperature Poly-Si TFTs on a Glass Substrate and a Novel and Unique Sensing Method", IEEE JOURNAL OF SOLID-STATE CIRCUITS, February 2003, vol. 38, no. 2, pages 274-280.				
EXAMINER	<i>M. Kramshayg</i>				DATE CONSIDERED <i>12/11/05</i>	
Examiner:	Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.					

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EXAMINER	<i>M. Transhaya</i>			DATE CONSIDERED <i>12/19/05</i>	
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